

# JEOL 7000F scanning electron microscope



This Schottky emission gun SEM (1.2 nm resolution at 30kV) is equipped with a conventional Everhart-Thornley secondary detector, a retractable DEBEN-BSED-GEN5 backscatter detector, an Oxford Aztec EDS (energy-dispersive spectrometer) and EBSD (electron backscatter diffraction) system.

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Phone: 508-831-6025

Location: Higgins Lab 047

# JEOL 100 CXII transmission electron microscope



This conventional TEM is equipped with a Gatan Orius 830 CCD camera, capable of electron diffraction and diffraction contrast imaging.

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Location: Olin Hall 028

# PANalytical Empyrean x-ray diffractometer



This is a multi-function x-ray diffractometer, capable of carrying out powder diffraction, stress analysis, texture analysis, x-ray reflectivity analysis and small-angle x-ray scattering.

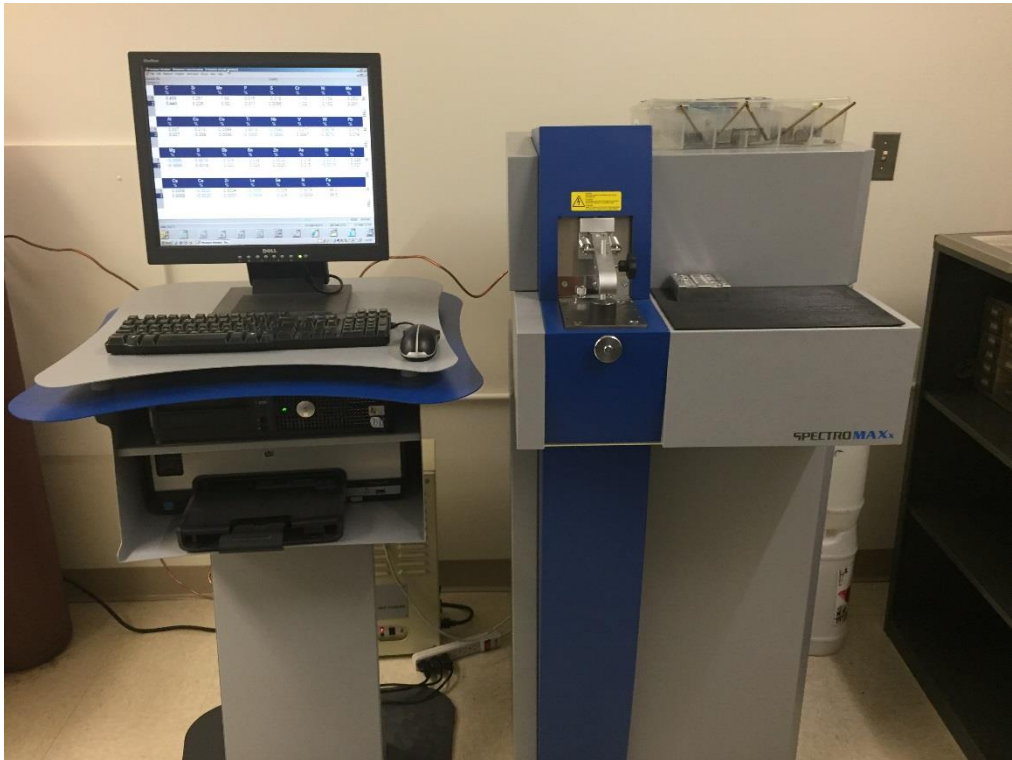
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Location: Washburn 231

# SPECTRO MAXx LMX04 Optical emission spectrometer



This spectrometer is used for accurate chemical analysis of metals and alloys.

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Location: Washburn 113

# Other equipment

- 1 Olympus inverted optical microscope (WB336)
- 1 Clark CM-400AT microhardness tester (WB336)
- 1 Shimazu HMV-200 microhardness tester (WB336)
- 3 Rockwell hardness testers (WB336)
- 1 Buehler microhardness tester (WB336)
- 3 Buehler vibromet I polishers (WB341)
- 2 Pace Nano 2000T grinder-polishers (WB341)
- 3 Century polishers (WB341)
- 1 EMS sputter coater (HL047)
- 1 Buehler Electromet 4 electropolisher (WB341)
- 1 Fischione M110 twin-jet electropolisher (WB113)
- 1 Mark V 600 cut-off machine (WB341)

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